

Mapping Option

MProbe Thin Film Measurement System

It is easy to be an expert with MProbe

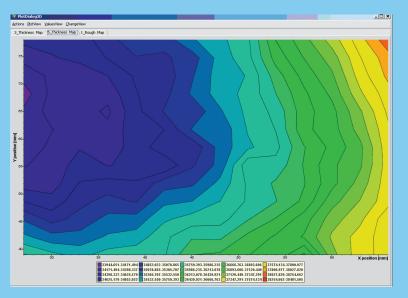
Majority of translucent or lightly absorbing films can be measured quickly and reliably:Oxides,Nitrides, Photoresists, Polymers, Semiconductors (Si, aSi, polySi), Hard coatings (SiC, DLC), Polymer coatings (Parylene, PMMA, Polyamides), thin metal films and many more.

Thickness and other parameters uniformity measurement are important for many applications.

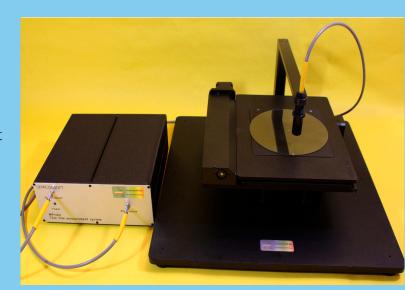
Mapping Option include:

- 1. XY motorized stage (150,200 and 300mm travel)
- 2. Solid 19x19" aluminum platform
- 3. Probe holder (Reflectance and/or transmittance measurement options are available) with optical system
- 4. Stage contoller
- 5. Software support (mapping recipes, etc.)

Hardware options	
-150XYM	6"x6" (150x150mm) XY motorized
	stage
-200XYM	8 x8"(200x200mm) XY motor-
	ized stage
-300XYM	12x12"(300x300mm) XY motor- ized stage
-VAC	Vacuum chuck (Sample holder insert with microholes and a motor pump)

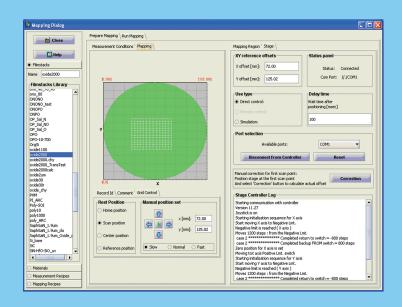


Contour map of the thickness measurement (thickness color coded)



MProbe system with mapping option

Position precision	< 2 \(\mu \) m
Resolution	< 0.5 μm
Drive	Stepper motor
Controller	Integrated with stage
Communication	Serial port (RS232)
Dimension	19" x 19" x 10" (for 6" and 8" stages)
Weight	12 kg



Mapping recipe setup and running

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